N-channel TrenchPLUS standard level FET

Rev. 02 — 10 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS diodes for temperature sensing and ElectroStatic Discharge (ESD) protection. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Allows responsive temperature monitoring due to integrated temperature sensor
- Electrostatically robust due to integrated protection diodes

1.3 Applications

 Electrical Power Assisted Steering (EPAS)

- Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for standard level gate drive sources
- Variable Valve Timing for engines

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	40	V
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } Figure 7; \text{ see}$ Figure 8	-	4.5	5	mΩ
$S_{F(TSD)}$	temperature sense diode temperature coefficient	l _F = 250 μA; T _j ≥ -55 °C; T _j ≤ 175 °C	-1.4	-1.54	-1.68	mV/K
V _{F(TSD)}	temperature sense diode forward voltage	I _F = 250 μΑ; Τ _j = 25 °C	648	658	668	mV
V _{F(TSD)hys}	temperature sense diode forward voltage hysteresis	I _F ≤ 250 μA; T _j = 25 °C; I _F ≥ 125 μA	25	32	50	mV



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2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	А	anode	mb	
3	D	drain		
4	К	cathode	i i !'	(☆ └ 平)
5	S	source		
mb	D	mounting base; connected to		S K
		drain	SOT426 (D2PAK)	mbl317

3. Ordering information

Table 3.Ordering information

Type number	Package		
	Name	Description	Version
BUK7105-40ATE	D2PAK	plastic single-ended surface-mounted package (D2PAK); 5 leads (one lead cropped)	SOT426

4. Limiting values

Table 4. Limiting values

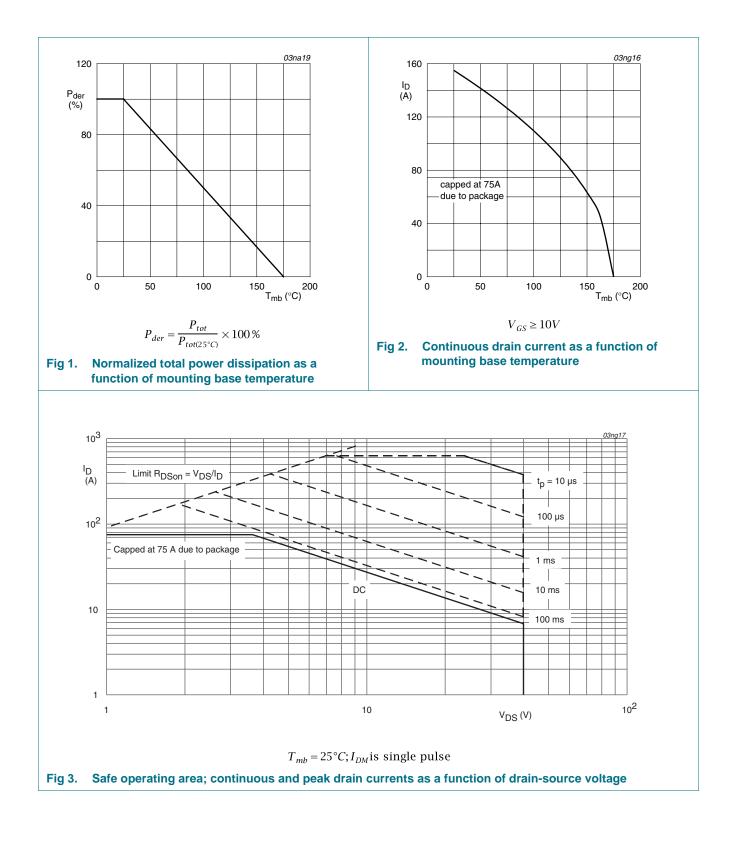
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	40	V
V _{GS}	gate-source voltage			-20	20	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } Figure 2; \text{ see } Figure 3$	[1]	-	155	А
			[2]	-	75	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 2</u>	[2]	-	75	А
I _{DM}	peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed}; \text{ see } \frac{\text{Figure } 3}{10 \mu\text{s}}$		-	620	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>		-	272	W
I _{GS(CL)}	gate-source clamping	continuous		-	10	mA
	current	pulsed; $t_p = 5 \text{ ms}; \delta = 0.01$		-	50	mA
Visol(FET-TSD)	FET to temperature sense diode isolation voltage			-100	100	V
T _{stg}	storage temperature			-55	175	°C
Т _ј	junction temperature			-55	175	°C
Source-drai	n diode					
I _S	source current	T _{mb} = 25 °C	[1]	-	155	А
			[2]	-	75	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^\circ C$		-	620	А
Avalanche r	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ I_D = 75 \text{ A}; \text{V}_{sup} \leq 40 \text{ V}; \text{R}_{GS} = 50 \Omega; \text{V}_{GS} = 10 \text{ V}; \\ \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped} $		-	1.46	J
Electrostati	c discharge					
V _{esd}	electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	6	kV

[1] Current is limited by power dissipation chip rating.

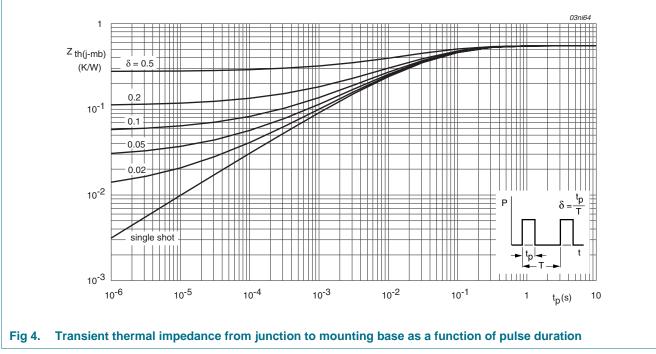
[2] Continuous current is limited by package.

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5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-a)}	thermal resistance from junction to ambient	mounted on a printed-circuit board; minimum footprint	-	50	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	0.55	K/W



6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	40	-	-	V
	breakdown voltage	I_D = 0.25 mA; V_{GS} = 0 V; T_j = -55 °C	36	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 9	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 9</u>	1	-	-	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 9</u>	-	-	4.4	V
I _{DSS}	drain leakage current	V_{DS} = 40 V; V_{GS} = 0 V; T_j = 25 °C	-	0.1	10	μΑ
		V_{DS} = 40 V; V_{GS} = 0 V; T_j = 175 °C	-	-	250	μA
()	gate-source breakdown voltage	$ \begin{array}{l} I_{G} = 1 \text{ mA}; \ V_{DS} = 0 \ V; \ T_{j} \leq 175 \ ^{\circ}C; \\ T_{j} \geq \text{-}55 \ ^{\circ}C \end{array} $	20	22	-	V
		$I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \le 175 \text{ °C};$ $T_j \ge -55 \text{ °C}$	20	22	-	V
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = 10 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = -10 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 175 \text{ °C}$	-	-	10	μA
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 175 \text{ °C}$	-	-	10	μΑ
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 \text{ °C};$ see Figure 7; see Figure 8	-	4.5	5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	9.5	mΩ
V _{F(TSD)}	temperature sense diode forward voltage	I _F = 250 μA; T _j = 25 °C	648	658	668	mV
S _{F(TSD)}	temperature sense diode temperature coefficient	I _F = 250 μA; T _j ≥ -55 °C; T _j ≤ 175 °C	-1.4	-1.54	-1.68	mV/K
V _{F(TSD)hys}	temperature sense diode forward voltage hysteresis	I _F ≤ 250 μA; I _F ≥ 125 μA; T _j = 25 °C	25	32	50	mV
Dynamic o	characteristics					
Q _{G(tot)}	total gate charge	I_D = 25 A; V_{DS} = 32 V; V_{GS} = 10 V;	-	118	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 14</u>	-	16	-	nC
Q _{GD}	gate-drain charge		-	57	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	4500	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	1500	-	pF
C _{rss}	reverse transfer capacitance		-	960	-	pF

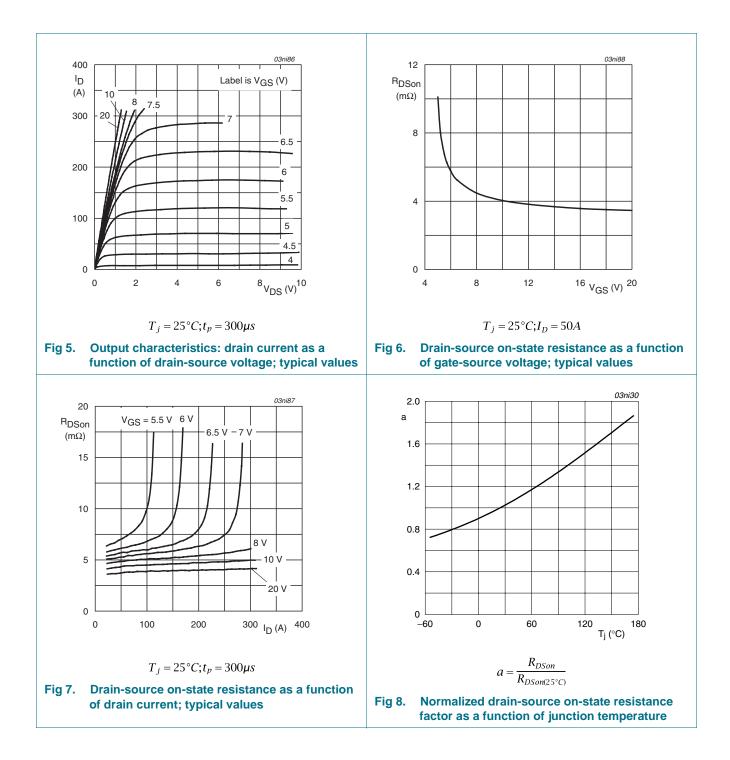
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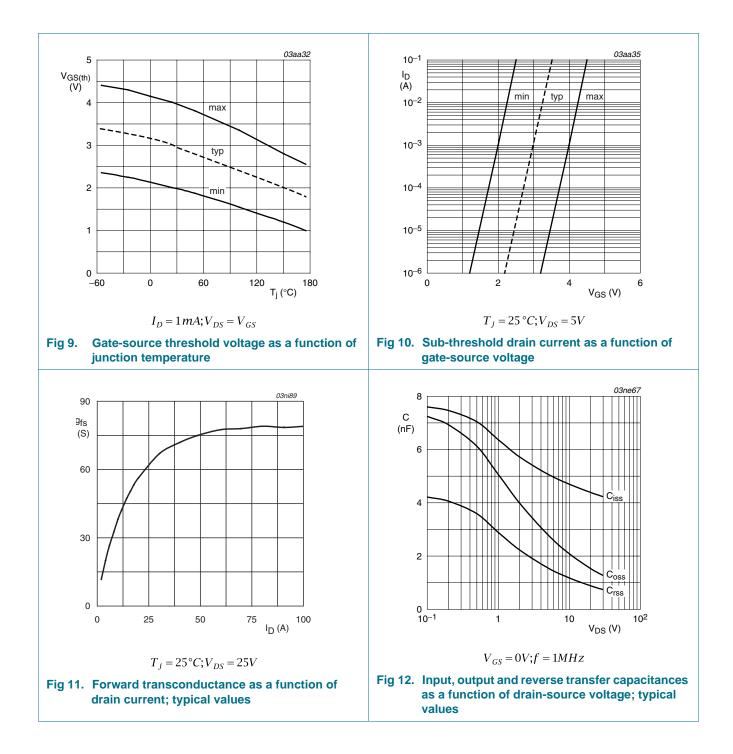
Table 6.	Characteristics contin	nued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	35	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	115	-	ns
t _{d(off)}	turn-off delay time		-	155	-	ns
t _f	fall time		-	110	-	ns
L _D	internal drain inductance	from upper edge of mounting base to centre of die; T _j = 25 °C	-	2.5	-	nH
L _S	internal source inductance	from source lead to source bond pad; $T_j = 25 \ ^{\circ}C$	-	7.5	-	nH
Source-d	rain diode					
V_{SD}	source-drain voltage	I _S = 40 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 17</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	I_{S} = 20 A; dI _S /dt = -100 A/µs; V _{GS} = -10 V;	-	96	-	ns
Qr	recovered charge	$V_{DS} = 30 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	224	-	nC

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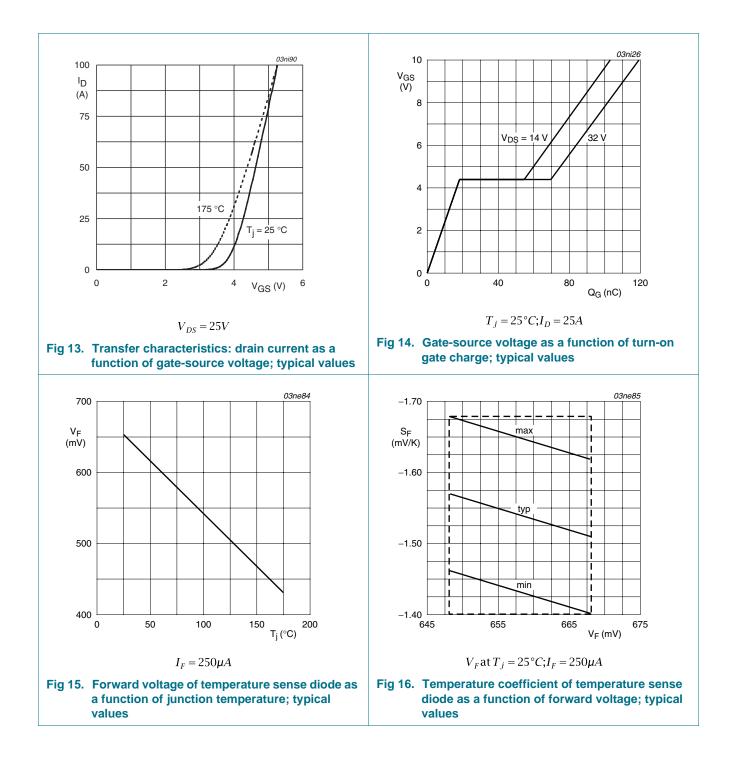
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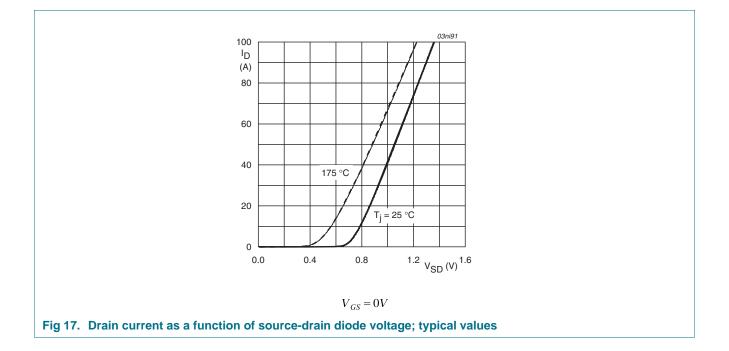


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7. Package outline

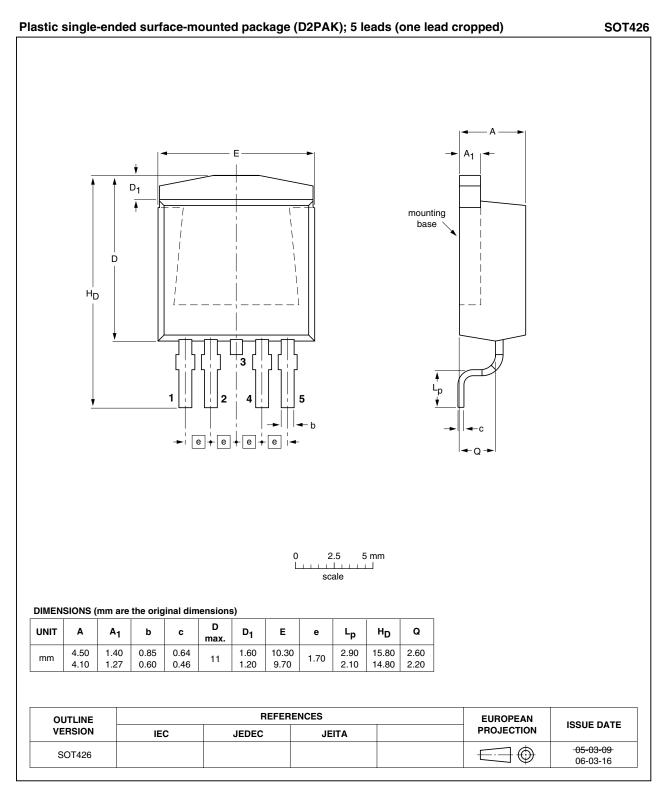


Fig 18. Package outline SOT426 (D2PAK)

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8. Revision history

Table 7. Revision hist	ory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7105-40ATE_2	20090210	Product data sheet	-	BUK71_7905_40ATE-01
Modifications:		of this data sheet has be of NXP Semiconductors.	een redesigned to comply	y with the new identity
	 Legal texts 	have been adapted to th	e new company name w	here appropriate.
	 Type numb 	er BUK7105-40ATE sepa	arated from data sheet B	UK71_7905_40ATE-01.
BUK71_7905_40ATE-01 (9397 750 11694)	20030820	Product data sheet	-	-

BUK7105-40ATE_2

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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